

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/786,388	STRECK ET AL.
Examiner	Art Unit	
Binh X. Tran	1765	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	746	1/11/2007	BT
438	747	1/11/2007	BT
438	756	1/11/2007	BT
438/770		1/11/2007	BT